

Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BC857AW Part Description											
									Nexperia DHAM Small Signal Bipolar Transistor				
									SMD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects							
			TEST										
			Pre- and Post-Stress										
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below							
		JESD22-A113 Bake Tamb = 125 °C	24 hours										
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours										
# A1	Preconditioning	Reflow soldering	3 cycles	1265	69890	0							
	HTRB High Temperature Reverse	MIL-STD-750-1 M1039 Method A Tj = Tjmax, Vr = 100% of max. datasheet											
# B1	Bias	reverse voltage	1000 hours	316	18920	0							
	тс	JESD22-A104											
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	260	15680	0							
# A3 or	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %											
" 7.5 C.		JESD22-A102	— 96 hours	270	16360	0							
	AC	Tamb = 121 °C, RH = 100 %											
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)											
# A2 alt	H3TRB High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000 hours	262	15760	0							
" / LZ CITC		MIL-STD-750 Method 1037											
	IOL	ton = toff, devices powered to insure ΔTj =											
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	262	15760	0							
	RSH	JESD22-A111											
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	211	6330	0							
# C10	SD Solderability	J-STD-002		468	4680	0							

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia	Small Signal Bipolar				
DHAM	Transistor	18920	0	0,22	4,46E+09

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